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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I ² C, IrDA, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	34
Program Memory Size	32KB (16K x 16)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 12x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	0°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	49-VFBGA
Supplier Device Package	49-VFBGA (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atxmega32a4u-cn

20. RTC – 16-bit Real-Time Counter

20.1 Features

- 16-bit resolution
- Selectable clock source
 - 32.768kHz external crystal
 - External clock
 - 32.768kHz internal oscillator
 - 32kHz internal ULP oscillator
- Programmable 10-bit clock prescaling
- One compare register
- One period register
- Clear counter on period overflow
- Optional interrupt/event on overflow and compare match

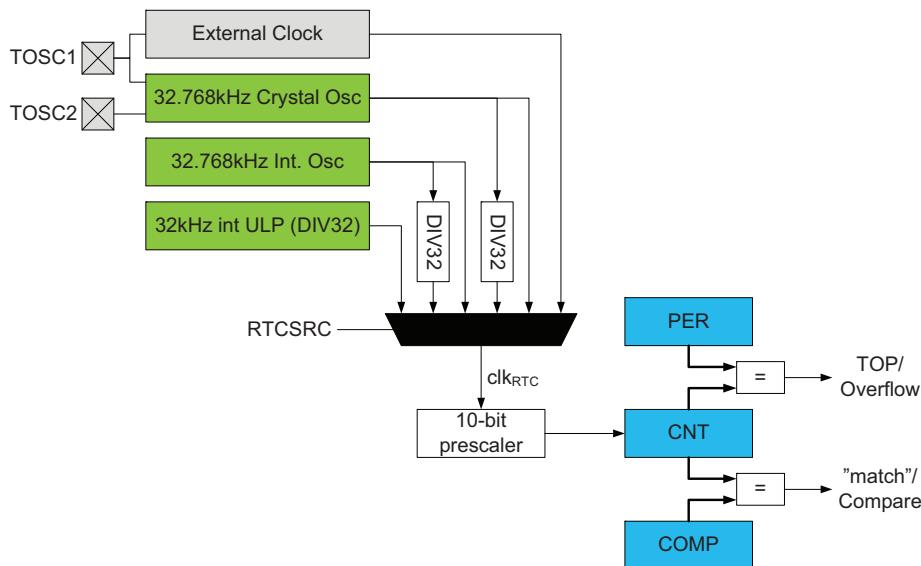
20.2 Overview

The 16-bit real-time counter (RTC) is a counter that typically runs continuously, including in low-power sleep modes, to keep track of time. It can wake up the device from sleep modes and/or interrupt the device at regular intervals.

The reference clock is typically the 1.024kHz output from a high-accuracy crystal of 32.768kHz, and this is the configuration most optimized for low power consumption. The faster 32.768kHz output can be selected if the RTC needs a resolution higher than 1ms. The RTC can also be clocked from an external clock signal, the 32.768kHz internal oscillator or the 32kHz internal ULP oscillator.

The RTC includes a 10-bit programmable prescaler that can scale down the reference clock before it reaches the counter. A wide range of resolutions and time-out periods can be configured. With a 32.768kHz clock source, the maximum resolution is 30.5 μ s, and time-out periods can range up to 2000 seconds. With a resolution of 1s, the maximum timeout period is more than 18 hours (65536 seconds). The RTC can give a compare interrupt and/or event when the counter equals the compare register value, and an overflow interrupt and/or event when it equals the period register value.

Figure 20-1. Real-time counter overview.



21. USB – Universal Serial Bus Interface

21.1 Features

- One USB 2.0 full speed (12Mbps) and low speed (1.5Mbps) device compliant interface
- Integrated on-chip USB transceiver, no external components needed
- 16 endpoint addresses with full endpoint flexibility for up to 31 endpoints
 - One input endpoint per endpoint address
 - One output endpoint per endpoint address
- Endpoint address transfer type selectable to
 - Control transfers
 - Interrupt transfers
 - Bulk transfers
 - Isochronous transfers
- Configurable data payload size per endpoint, up to 1023 bytes
- Endpoint configuration and data buffers located in internal SRAM
 - Configurable location for endpoint configuration data
 - Configurable location for each endpoint's data buffer
- Built-in direct memory access (DMA) to internal SRAM for:
 - Endpoint configurations
 - Reading and writing endpoint data
- Ping-pong operation for higher throughput and double buffered operation
 - Input and output endpoint data buffers used in a single direction
 - CPU/DMA controller can update data buffer during transfer
- Multipacket transfer for reduced interrupt load and software intervention
 - Data payload exceeding maximum packet size is transferred in one continuous transfer
 - No interrupts or software interaction on packet transaction level
- Transaction complete FIFO for workflow management when using multiple endpoints
 - Tracks all completed transactions in a first-come, first-served work queue
- Clock selection independent of system clock source and selection
- Minimum 1.5MHz CPU clock required for low speed USB operation
- Minimum 12MHz CPU clock required for full speed operation
- Connection to event system
- On chip debug possibilities during USB transactions

21.2 Overview

The USB module is a USB 2.0 full speed (12Mbps) and low speed (1.5Mbps) device compliant interface.

The USB supports 16 endpoint addresses. All endpoint addresses have one input and one output endpoint, for a total of 31 configurable endpoints and one control endpoint. Each endpoint address is fully configurable and can be configured for any of the four transfer types; control, interrupt, bulk, or isochronous. The data payload size is also selectable, and it supports data payloads up to 1023 bytes.

No dedicated memory is allocated for or included in the USB module. Internal SRAM is used to keep the configuration for each endpoint address and the data buffer for each endpoint. The memory locations used for endpoint configurations and data buffers are fully configurable. The amount of memory allocated is fully dynamic, according to the number of endpoints in use and the configuration of these. The USB module has built-in direct memory access (DMA), and will read/write data from/to the SRAM when a USB transaction takes place.

To maximize throughput, an endpoint address can be configured for ping-pong operation. When done, the input and output endpoints are both used in the same direction. The CPU or DMA controller can then read/write one data buffer while the USB module writes/reads the others, and vice versa. This gives double buffered communication.

Table 36-3. Operating voltage and frequency.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Clk _{CPU}	CPU clock frequency	V _{CC} = 1.6V	0		12	MHz
		V _{CC} = 1.8V	0		12	
		V _{CC} = 2.7V	0		32	
		V _{CC} = 3.6V	0		32	

The maximum CPU clock frequency depends on V_{CC}. As shown in [Figure 36-1](#) the Frequency vs. V_{CC} curve is linear between 1.8V < V_{CC} < 2.7V.

Figure 36-1. Maximum Frequency vs. V_{CC}.

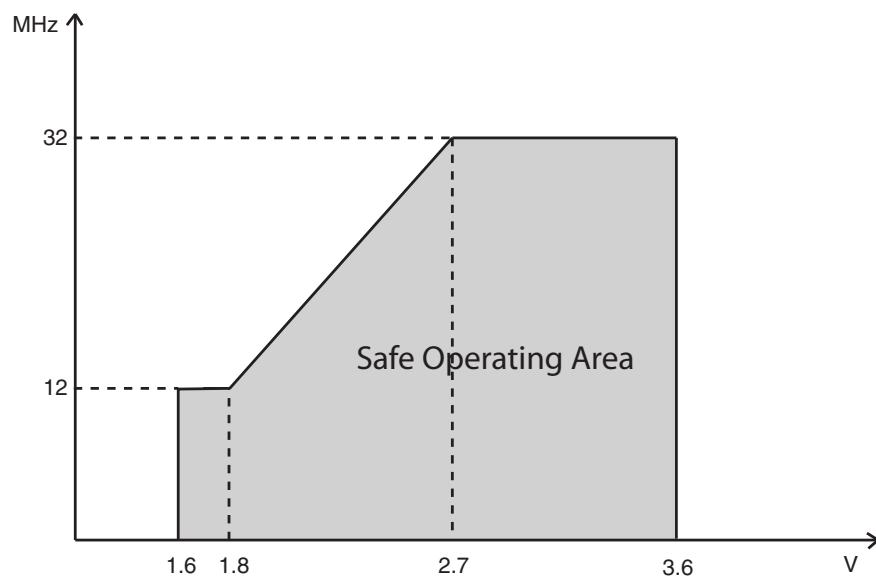


Table 36-37. Current consumption for modules and peripherals.

Symbol	Parameter	Condition ⁽¹⁾	Min.	Typ.	Max.	Units
I _{CC}	ULP oscillator			1.0		µA
	32.768kHz int. oscillator			27		µA
	2MHz int. oscillator			85		µA
		DFLL enabled with 32.768kHz int. osc. as reference		115		µA
	32MHz int. oscillator			270		µA
		DFLL enabled with 32.768kHz int. osc. as reference		460		µA
	PLL	20x multiplication factor, 32MHz int. osc. DIV4 as reference		220		µA
	Watchdog timer			1.0		µA
	BOD	Continuous mode		138		µA
		Sampled mode, includes ULP oscillator		1.2		µA
	Internal 1.0V reference			100		µA
	Temperature sensor			95		µA
	ADC	250ksps $V_{REF} = \text{Ext ref}$		3.0		mA
			CURRLIMIT = LOW	2.6		mA
			CURRLIMIT = MEDIUM	2.1		mA
			CURRLIMIT = HIGH	1.6		mA
	DAC	250ksps $V_{REF} = \text{Ext ref}$ No load	Normal mode	1.9		mA
			Low power mode	1.1		mA
	AC	High speed mode		330		µA
		Low power mode		130		µA
	DMA	615kbps between I/O registers and SRAM		108		µA
	Timer/counter			16		µA
	USART	Rx and Tx enabled, 9600 BAUD		2.5		µA
	Flash memory and EEPROM programming			4.0	8.0	mA

Note: 1. All parameters measured as the difference in current consumption between module enabled and disabled. All data at $V_{CC} = 3.0V$, $\text{Clk}_{SYS} = 1\text{MHz}$ external clock without prescaling, $T = 25^\circ\text{C}$ unless other conditions are given.

36.2.6 ADC characteristics

Table 36-40. Power supply, reference and input range.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{CC}	Analog supply voltage		$V_{CC} - 0.3$		$V_{CC} + 0.3$	V
V_{REF}	Reference voltage		1		$V_{CC} - 0.6$	V
R_{in}	Input resistance	Switched		4.0		kΩ
C_{sample}	Input capacitance	Switched		4.4		pF
R_{AREF}	Reference input resistance	(leakage only)		>10		MΩ
C_{AREF}	Reference input capacitance	Static load		7		pF
V_{IN}	Input range		-0.1		$V_{CC} + 0.1$	V
	Conversion range	Differential mode, $V_{INP} - V_{INN}$	$-V_{REF}$		V_{REF}	V
	Conversion range	Single ended unsigned mode, V_{INP}	$-\Delta V$		$V_{REF} - \Delta V$	V
ΔV	Fixed offset voltage			190		LSB

Table 36-41. Clock and timing.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Clk_{ADC}	ADC clock frequency	Maximum is 1/4 of peripheral clock frequency	100		2000	kHz
		Measuring internal signals	100		125	
f_{ADC}	Sample rate	Current limitation (CURRLIMIT) off	100		2000	ksps
		CURRLIMIT = LOW	100		1500	
		CURRLIMIT = MEDIUM	100		1000	
		CURRLIMIT = HIGH	100		500	
	Sampling time	1/2 Clk_{ADC} cycle	0.25		5	μs
	Conversion time (latency)	$(RES+2)/2 + (GAIN != 0)$ RES (Resolution) = 8 or 12	5		8	Clk_{ADC} cycles
	Start-up time	ADC clock cycles		12	24	Clk_{ADC} cycles
	ADC settling time	After changing reference or input mode		7	7	Clk_{ADC} cycles
		After ADC flush		1	1	Clk_{ADC} cycles

Table 36-63. SPI timing characteristics and requirements.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t_{SCK}	SCK period	Master		(See Table 21-4 in XMEGA AU Manual)		ns
t_{SCKW}	SCK high/low width	Master		0.5×SCK		
t_{SCKR}	SCK rise time	Master		2.7		
t_{SCKF}	SCK fall time	Master		2.7		
t_{MIS}	MISO setup to SCK	Master		10		
t_{MIH}	MISO hold after SCK	Master		10		
t_{MOS}	MOSI setup SCK	Master		0.5×SCK		
t_{MOH}	MOSI hold after SCK	Master		1.0		
t_{SSCK}	Slave SCK Period	Slave	$4 \times t_{Clk_{PER}}$			
t_{SSCKW}	SCK high/low width	Slave	$2 \times t_{Clk_{PER}}$			
t_{SSCKR}	SCK rise time	Slave			1600	
t_{SSCKF}	SCK fall time	Slave			1600	
t_{SIS}	MOSI setup to SCK	Slave	3.0			
t_{SIH}	MOSI hold after SCK	Slave	$t_{Clk_{PER}}$			
t_{SSS}	\overline{SS} setup to SCK	Slave	21			
t_{SSH}	\overline{SS} hold after SCK	Slave	20			
t_{SOS}	MISO setup SCK	Slave		8.0		
t_{SOH}	MISO hold after SCK	Slave		13		
t_{SOSS}	MISO setup after \overline{SS} low	Slave		11		
t_{SOSH}	MISO hold after \overline{SS} high	Slave		8.0		

36.3 ATxmega64A4U

36.3.1 Absolute Maximum Ratings

Stresses beyond those listed in [Table 36-65](#) may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Table 36-65. Absolute maximum ratings.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{CC}	Power supply voltage		-0.3		4.0	V
I_{VCC}	Current into a V_{CC} pin				200	mA
I_{GND}	Current out of a Gnd pin				200	mA
V_{PIN}	Pin voltage with respect to Gnd and V_{CC}		-0.5		$V_{CC}+0.5$	V
I_{PIN}	I/O pin sink/source current		-25		25	mA
T_A	Storage temperature		-65		150	°C
T_j	Junction temperature				150	°C

36.3.2 General Operating Ratings

The device must operate within the ratings listed in [Table 36-66](#) in order for all other electrical characteristics and typical characteristics of the device to be valid.

Table 36-66. General operating conditions.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{CC}	Power supply voltage		1.60		3.6	V
$A V_{CC}$	Analog supply voltage		1.60		3.6	V
T_A	Temperature range		-40		85	°C
T_j	Junction temperature		-40		105	°C

Table 36-67. Operating voltage and frequency.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$C_{lk_{CPU}}$	CPU clock frequency	$V_{CC} = 1.6V$	0		12	MHz
		$V_{CC} = 1.8V$	0		12	
		$V_{CC} = 2.7V$	0		32	
		$V_{CC} = 3.6V$	0		32	

The maximum CPU clock frequency depends on V_{CC} . As shown in [Figure 36-15](#) the Frequency vs. V_{CC} curve is linear between $1.8V < V_{CC} < 2.7V$.

36.3.15 SPI Characteristics

Figure 36-19.SPI timing requirements in master mode.

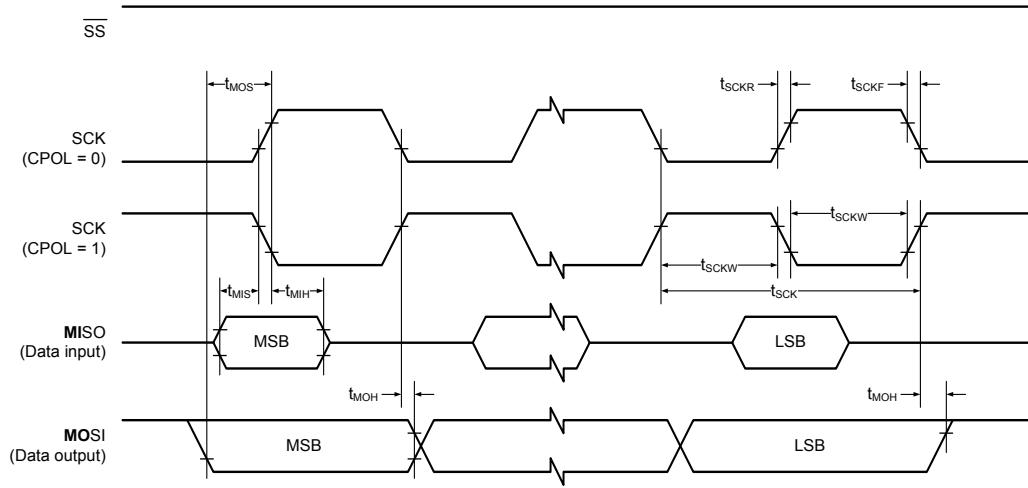


Figure 36-20.SPI timing requirements in slave mode.

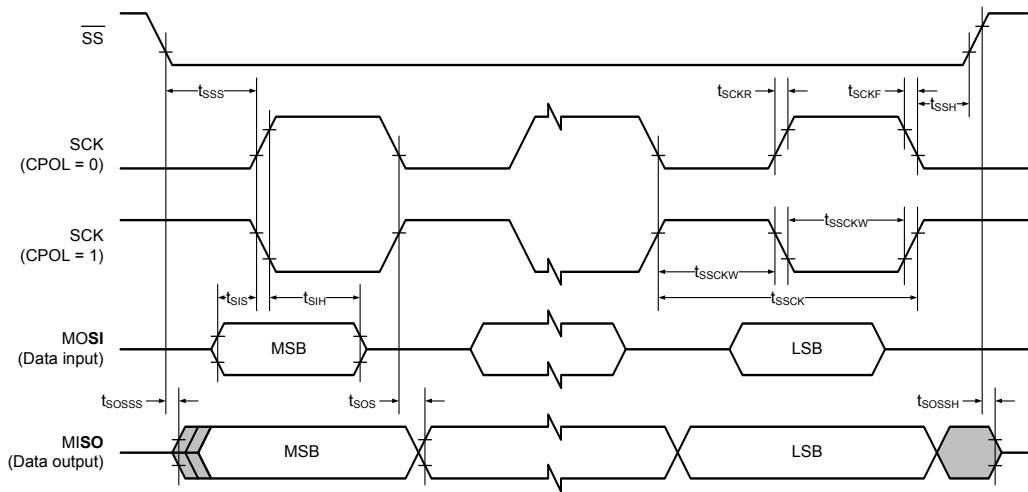


Table 36-110. Accuracy characteristics.

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
RES	Input resolution					12	Bits
INL ⁽¹⁾	Integral non-linearity	$V_{REF} = \text{Ext } 1.0V$	$V_{CC} = 1.6V$		± 2.0	± 3.0	lsb
			$V_{CC} = 3.6V$		± 1.5	± 2.5	
		$V_{REF} = AV_{CC}$	$V_{CC} = 1.6V$		± 2.0	± 4.0	
			$V_{CC} = 3.6V$		± 1.5	± 4.0	
		$V_{REF} = INT1V$	$V_{CC} = 1.6V$		± 5.0		
			$V_{CC} = 3.6V$		± 5.0		
DNL ⁽¹⁾	Differential non-linearity	$V_{REF} = \text{Ext } 1.0V$	$V_{CC} = 1.6V$		± 1.5	3.0	lsb
			$V_{CC} = 3.6V$		± 0.6	1.5	
		$V_{REF} = AV_{CC}$	$V_{CC} = 1.6V$		± 1.0	3.5	
			$V_{CC} = 3.6V$		± 0.6	1.5	
		$V_{REF} = INT1V$	$V_{CC} = 1.6V$		± 4.5		
			$V_{CC} = 3.6V$		± 4.5		
	Gain error	After calibration			<4.0		lsb
	Gain calibration step size				4.0		lsb
	Gain calibration drift	$V_{REF} = \text{Ext } 1.0V$			<0.2		mV/K
	Offset error	After calibration			<1.0		lsb
	Offset calibration step size				1.0		

Note: 1. Maximum numbers are based on characterisation and not tested in production, and valid for 5% to 95% output voltage range.

Figure 37-5. Active mode supply current vs. V_{CC} .

$f_{SYS} = 2\text{MHz}$ internal oscillator.

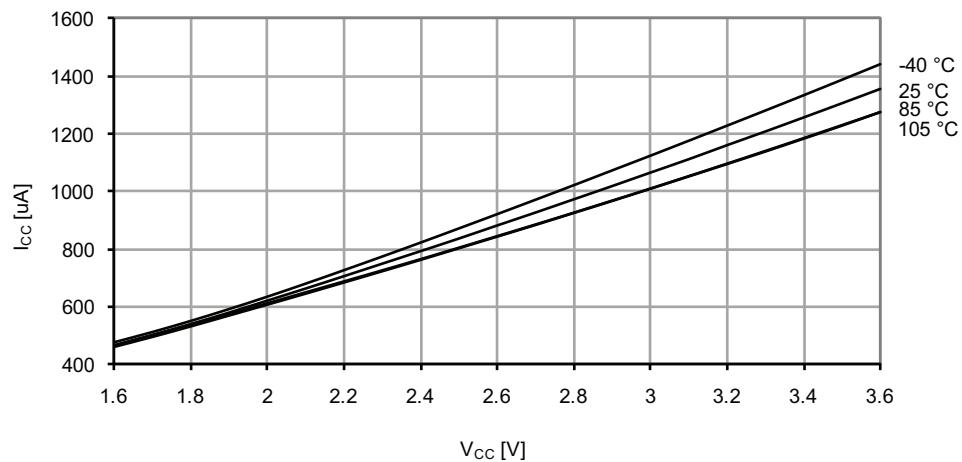
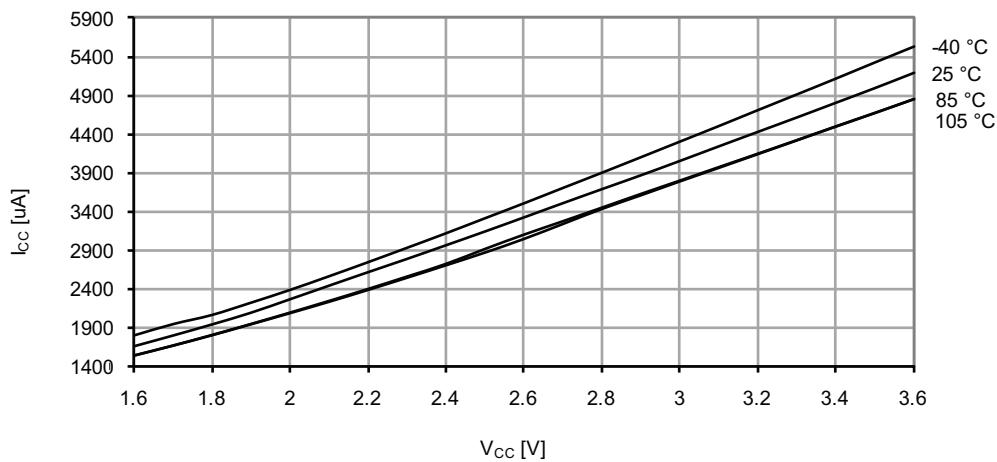


Figure 37-6. Active mode supply current vs. V_{CC} .

$f_{SYS} = 32\text{MHz}$ internal oscillator prescaled to 8MHz.



37.1.2 I/O Pin Characteristics

37.1.2.1 Pull-up

Figure 37-21. I/O pin pull-up resistor current vs. input voltage.

$V_{CC} = 1.8V$.

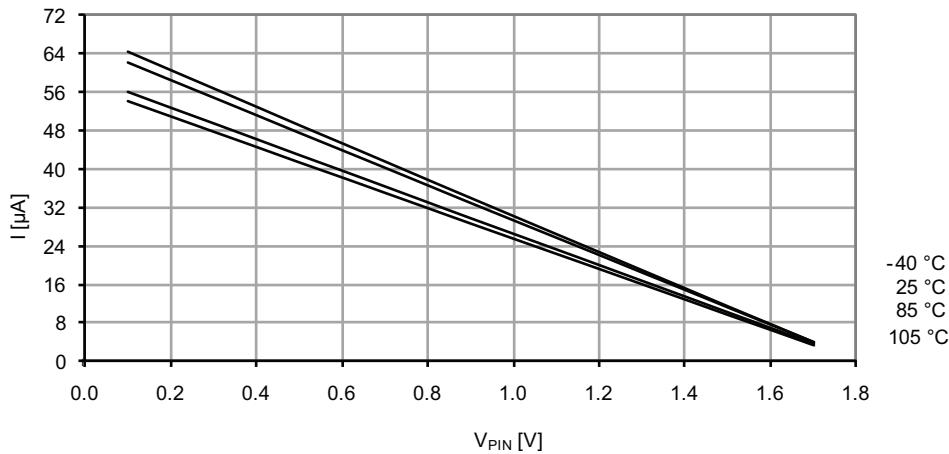


Figure 37-22. I/O pin pull-up resistor current vs. input voltage.

$V_{CC} = 3.0V$.

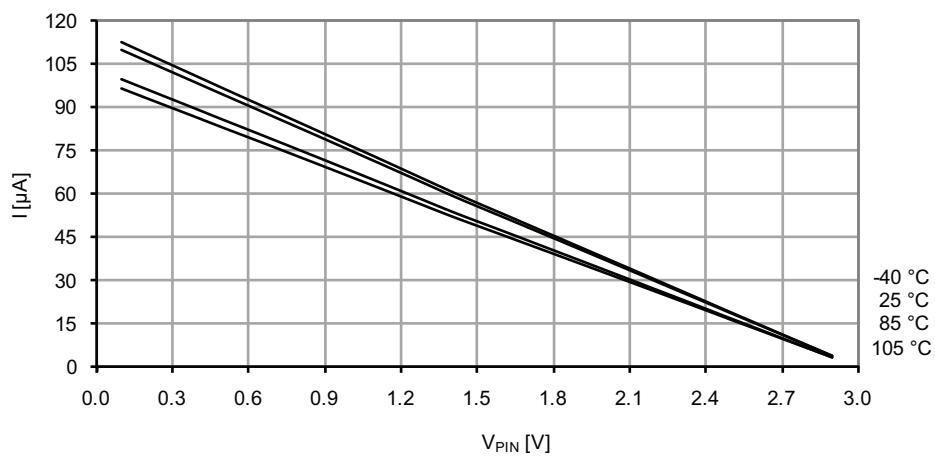


Figure 37-56. Analog comparator current source vs. calibration value.
 Temperature = 25°C.

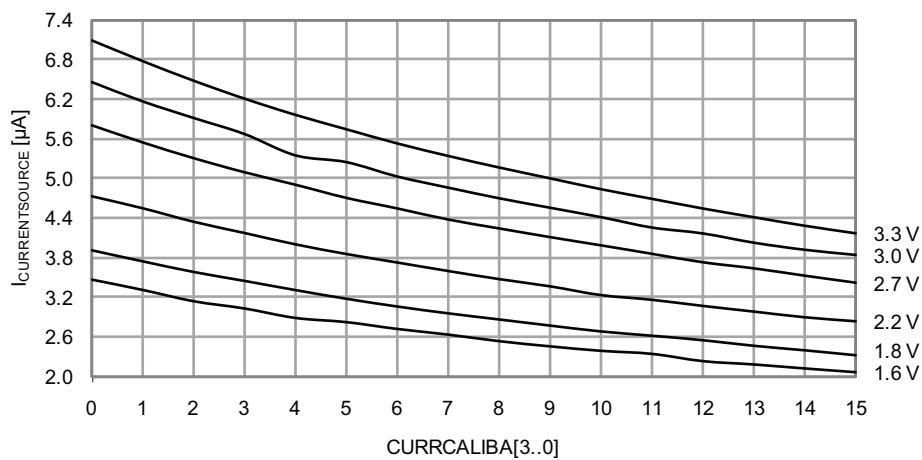


Figure 37-57. Analog comparator current source vs. calibration value.
 $V_{CC} = 3.0V$.

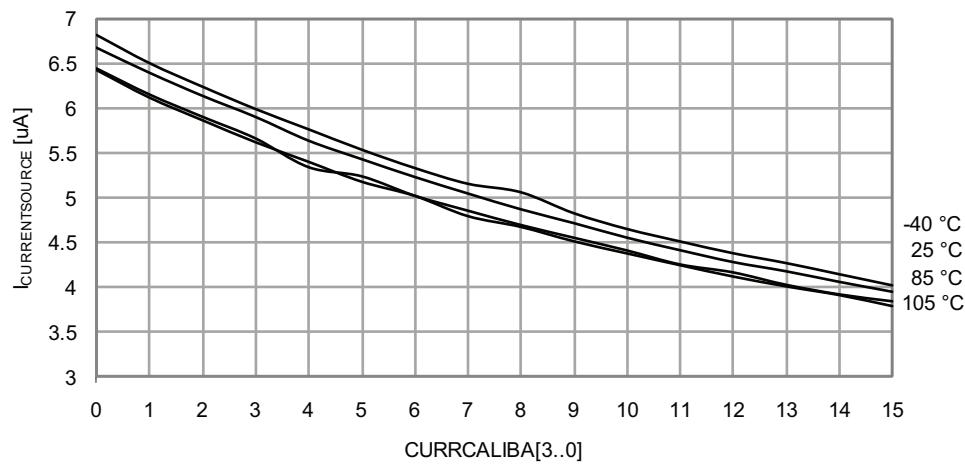


Figure 37-124. DNL error vs. sample rate.

$T = 25^\circ\text{C}$, $V_{CC} = 3.6\text{V}$, $V_{REF} = 3.0\text{V}$ external.

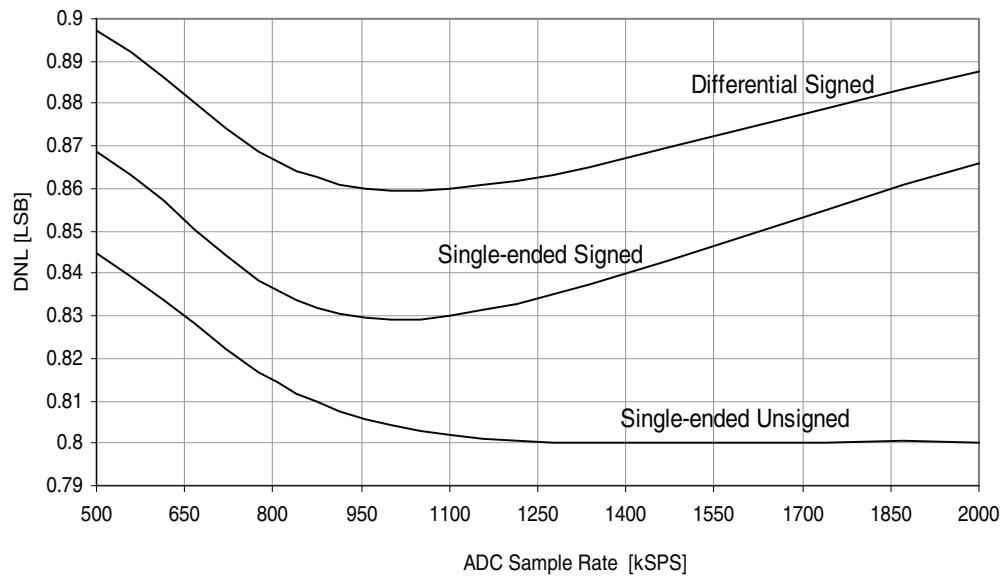


Figure 37-125. DNL error vs. input code.

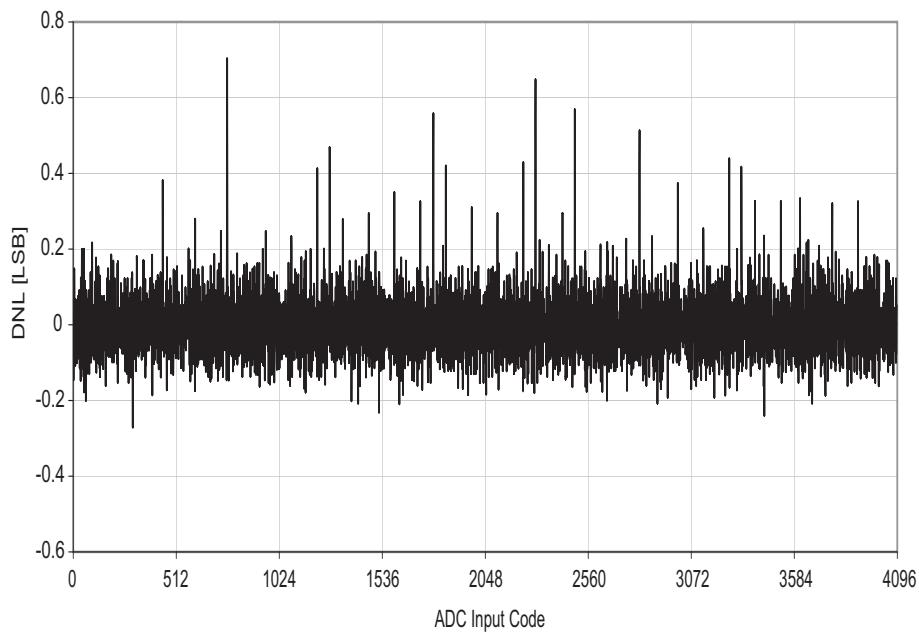
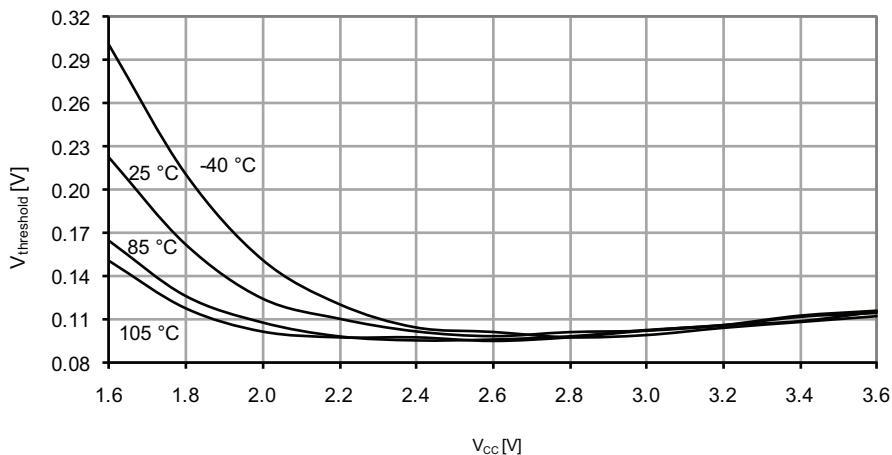


Figure 37-203. I/O pin input hysteresis vs. V_{CC} .



37.3.3 ADC Characteristics

Figure 37-204. INL error vs. external V_{REF} .

$T = 25^{\circ}\text{C}$, $V_{CC} = 3.6\text{V}$, external reference.

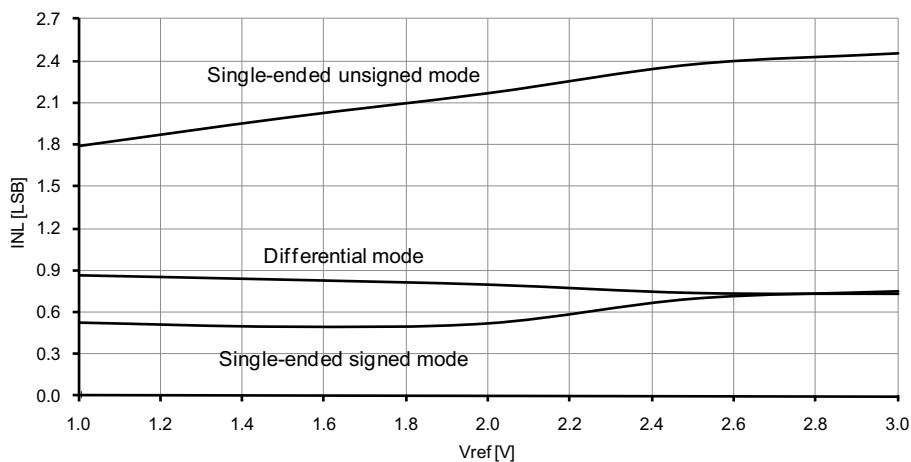


Figure 37-209. DNL error vs. input code.

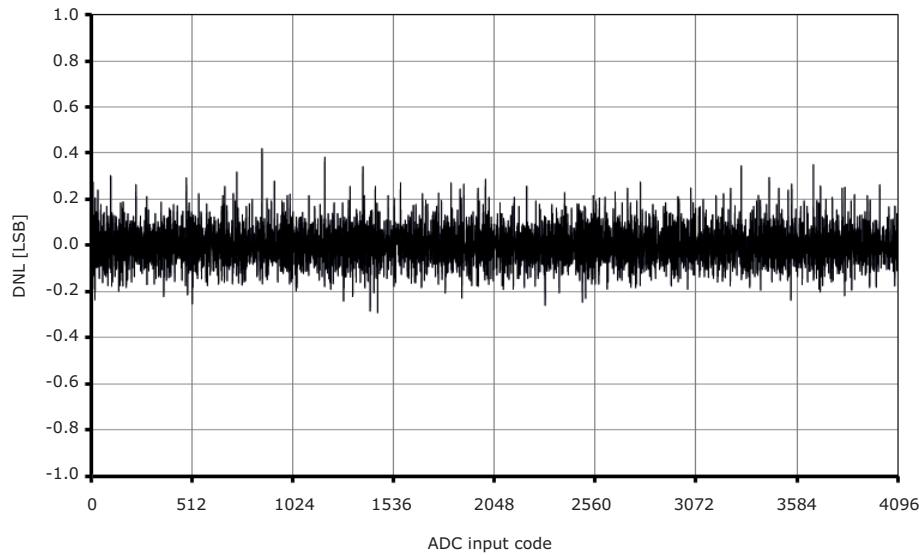


Figure 37-210. Gain error vs. V_{REF} .

$T = 25^\circ\text{C}$, $V_{CC} = 3.6\text{V}$, ADC sampling speed = 500ksps.

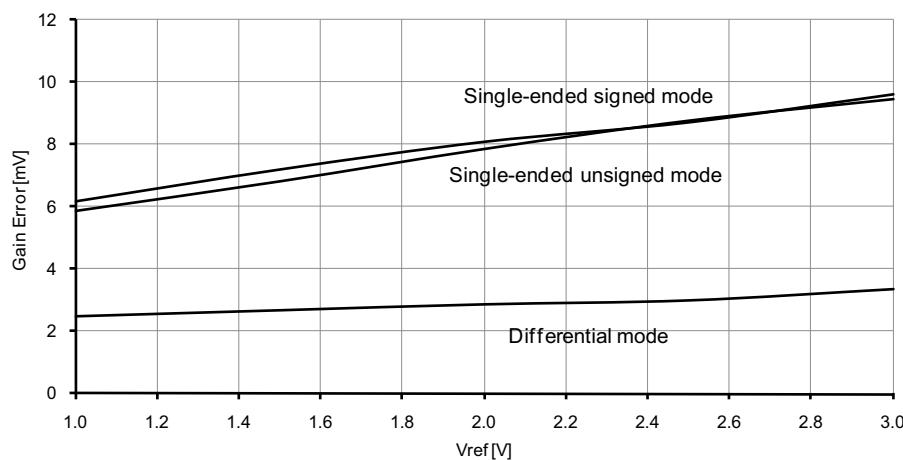
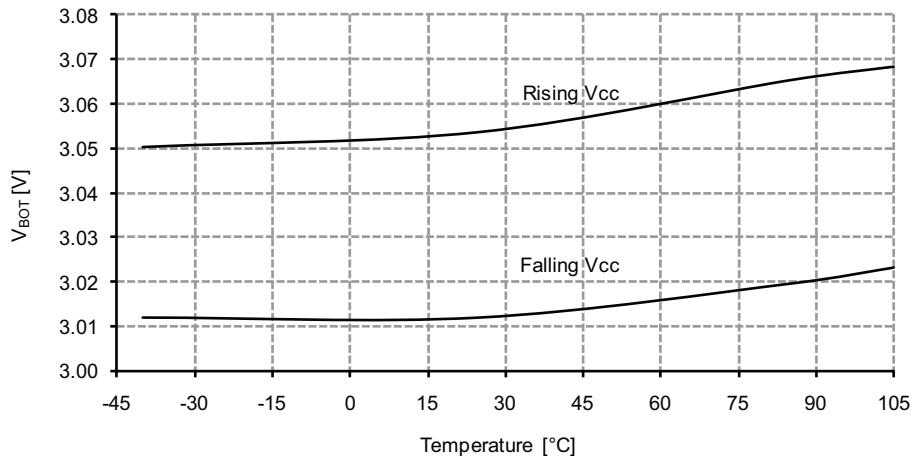


Figure 37-229. BOD thresholds vs. temperature.

BOD level = 3.0V.



37.3.8 External Reset Characteristics

Figure 37-230. Minimum Reset pin pulse width vs. V_{cc}.

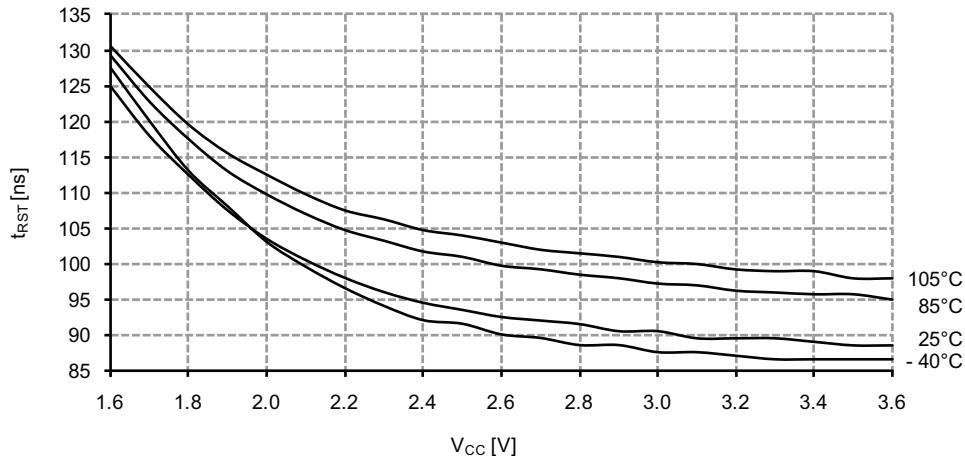
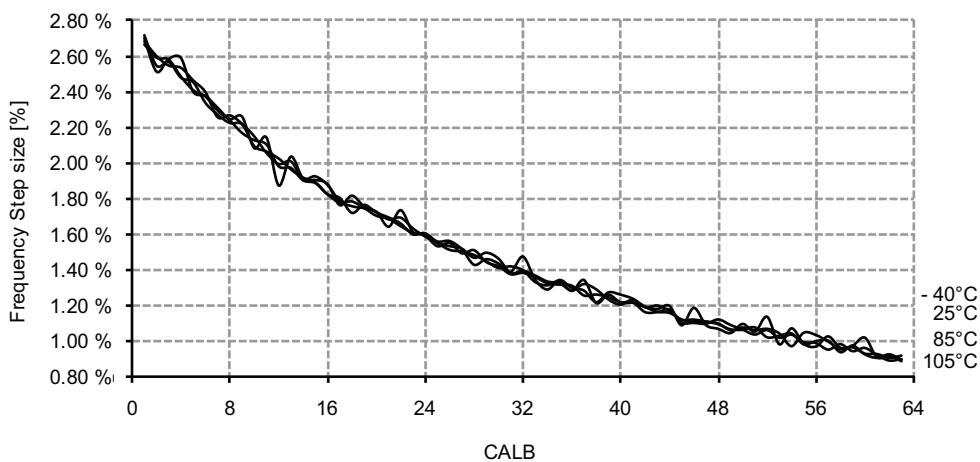


Figure 37-247. 32MHz internal oscillator CALB calibration step size.

$V_{CC} = 3.0V$



37.3.10.5 32MHz internal oscillator calibrated to 48MHz

Figure 37-248. 48MHz internal oscillator frequency vs. temperature.

DFLL disabled.

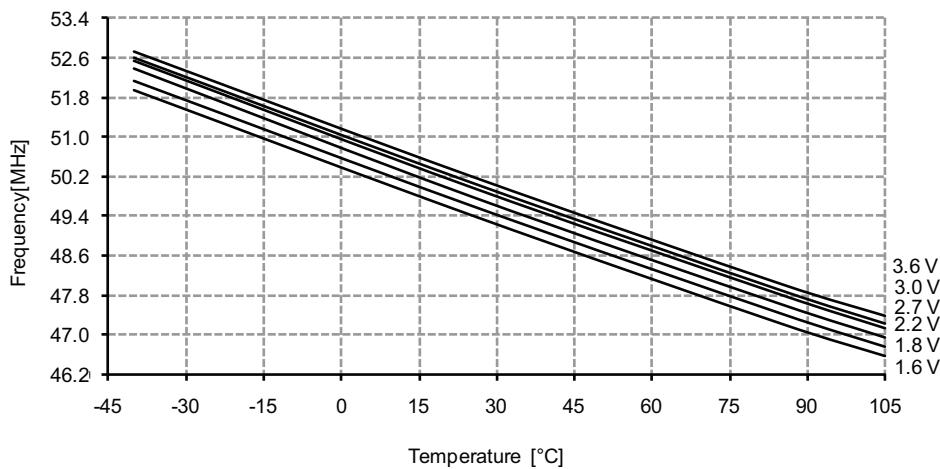


Figure 37-249. 48MHz internal oscillator frequency vs. temperature.
DFLL enabled, from the 32.768kHz internal oscillator.

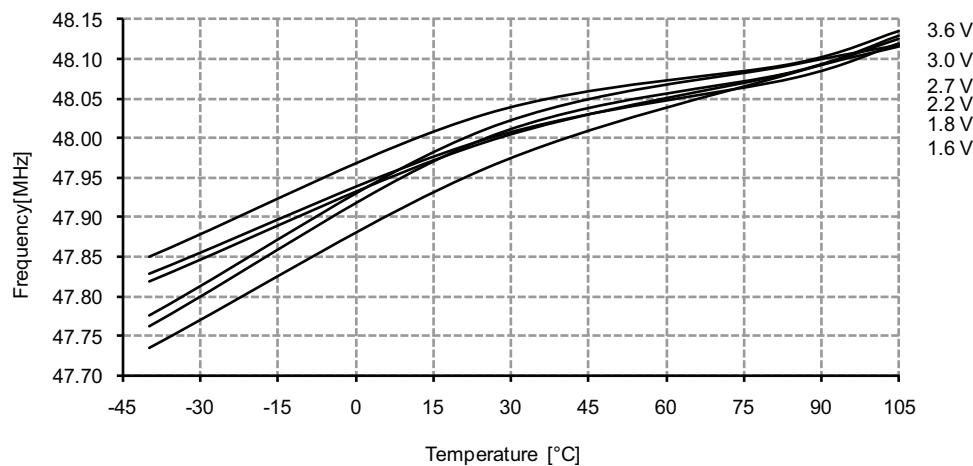


Figure 37-250. 48MHz internal oscillator CALA calibration step size.
 $V_{CC} = 3.0V$

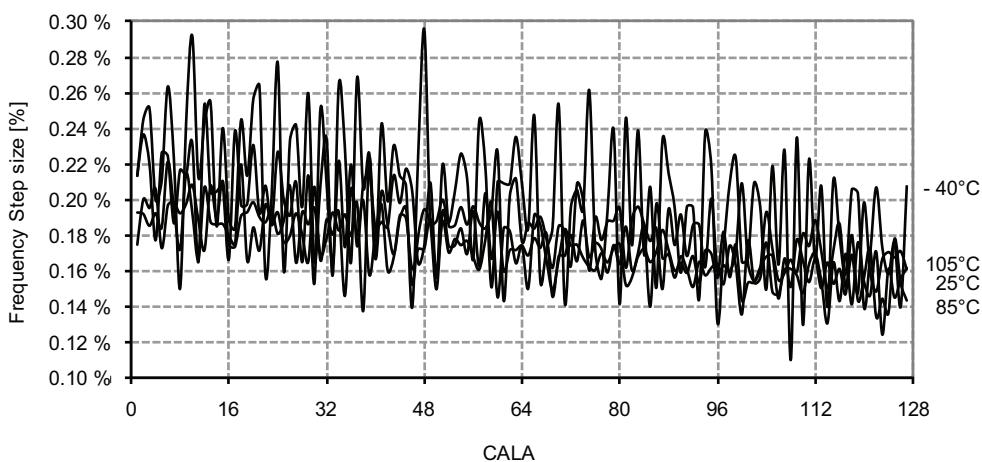


Figure 37-285. I/O pin input threshold voltage vs. V_{CC} .

V_{IH} I/O pin read as "1"

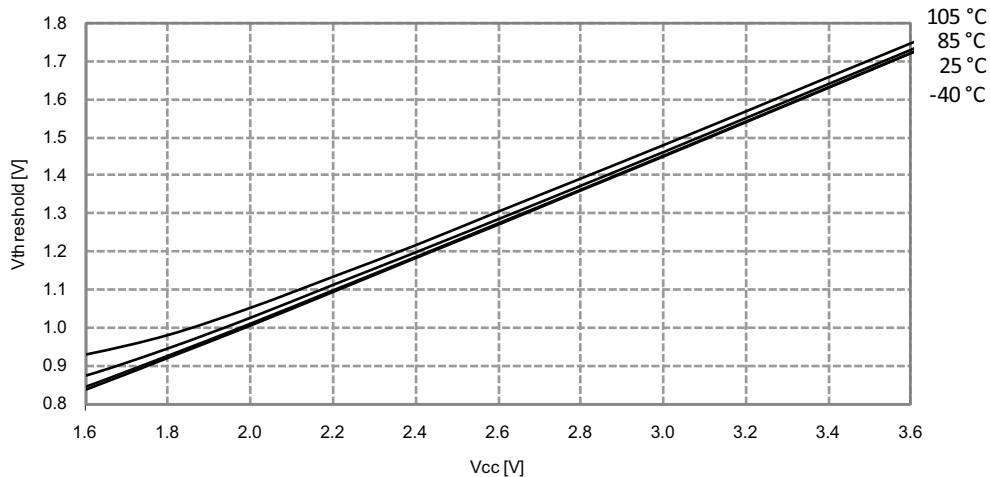
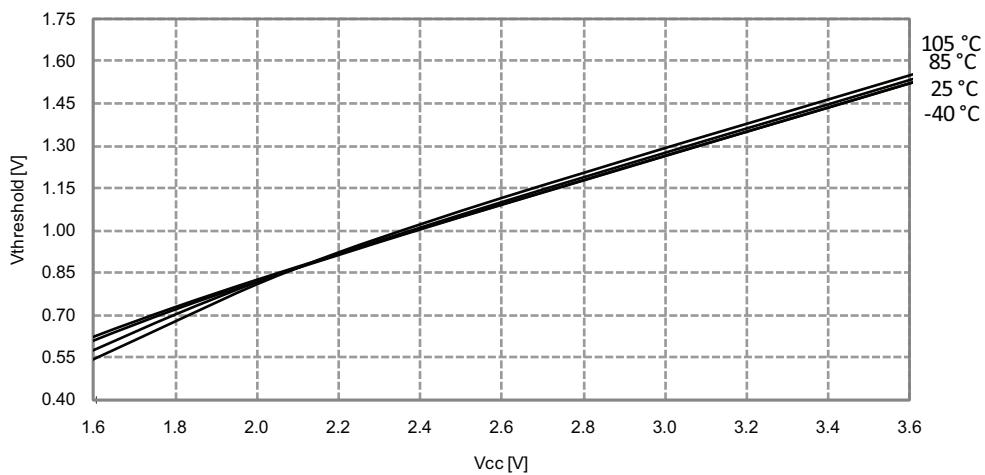


Figure 37-286. I/O pin input threshold voltage vs. V_{CC} .

V_{IL} I/O pin read as "0"



37.4.10.2 32.768kHz Internal Oscillator

Figure 37-323. 32.768kHz internal oscillator frequency vs. temperature

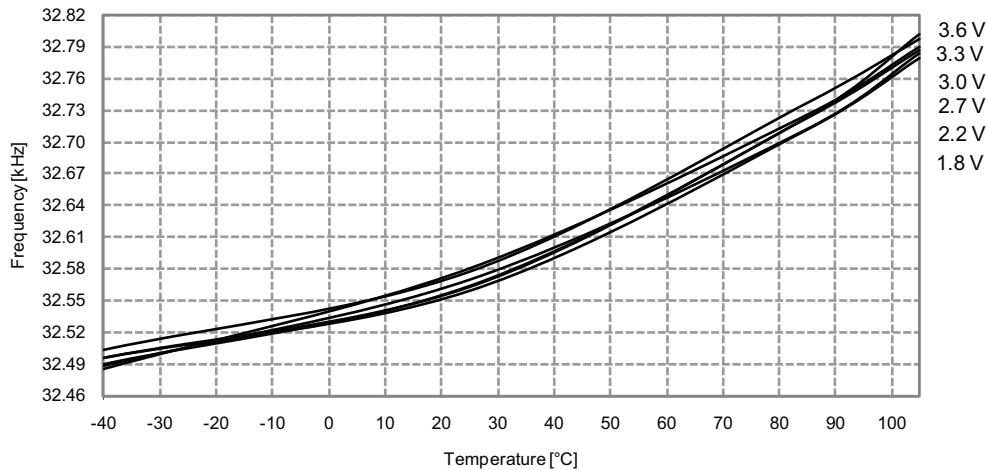


Figure 37-324. 32.768kHz internal oscillator frequency vs. calibration value

$V_{CC} = 3.0V, T = 25^{\circ}C$

